

<b>Search Notes (continued)</b> 	<b>Application/Control No.</b> 10/066,037	<b>Applicant(s)/Patent under Reexamination</b> CHEN ET AL.
	<b>Examiner</b> NAMITHA PILLAI	<b>Art Unit</b> 2172

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner